Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/766,971	BONG, YIN YEN
Examiner	Art Unit
Chris C. Chu	2815

	SEAR	CHED			
	SEARCHED				
Class	Subclass	Date	Examiner		
257	E23.19, E23.177 & E23.07	6/29/2006	C.C.		
257	E23.065	6/29/2006	C.C.		
257	678	6/29/2006	C.C.		

INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	6/29/2006	C.C.		